

**Search Notes**

Application/Control No.

10/522,481

Examiner

John D. Lee

Applicant(s)/Patent under  
Reexamination

CHA ET AL.

Art Unit

2874

**SEARCHED**

Class	Subclass	Date	Examiner
385	146,147, 901	7/26/2006	JDL
349	58,60	7/26/2006	JDL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
USPTO "WEST" Database searched; search strategy on separate sheet.	7/26/2006	JDL